



Concord Technology Supertest In-Circuit Tester T800FV

GOEPEL electronic's Boundary Scan Integration into Concord Technology In-Circuit Tester



Combine the advantages of In-Circuit Test and JTAG/Boundary Scan to get the best possible test coverage!

Advantages of In-Circuit Test

- Short test time
- Testing for short/opens
- Test of passive components
- Test of discrete logic
- Test of analogue components

Advantages of JTAG/Boundary Scan

- Standardised test method since 1990
- Test of highly complex digital devices like microprocessors, FPGAs and PLDs
- Test of memory and flash
- PLDs, EEPROMs and flash

Concord Technology Supertest T800FV

- High-speed accurate test increases throughput and improves PCBA quality and reliability
- Low-cost system user-friendly for unskilled operators helps reducing costs
- LAN support for statistic process control provides total solution

SCANBOOSTER™/USB-FXT Designer Studio and Run Time Studio

- Excellent price-performance ratio
- Multiple application levels (IC, ISP, system)
- Flexible and expandable architecture

Concord Technology Ltd.

Unit B, 4/F
Wing Cheon Ind*1 Bldg.,
121 King Lam Street

Lai Chi Kok, Kowloon

Tel: + (852) 23 10 28 28
sales@concord-tech.com
www.concord-tech.asia



GOEPEL electronics Asia Ltd.

Unit 223A, 2/F, Core Building 2
Hong Kong Science Park
Shatin, New Territories

Hong Kong

Tel: + (852) 61 92 21 51
sales@goepel.asia
www.goepel.asia

